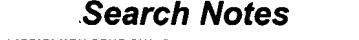


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/649,918	OKA ET AL.
	Examiner	Art Unit
	Syed Zaidi	2616

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	10/15/2007	SZ
Inventor : Oka et all	10/15/2007	SZ
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(370/328 370/329 370/330 370/331 370/338).CCLS.	10/15/2007	SZ
Consulted with SPE Seema S.Rao	10/15/2007	SZ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner